

## Electronic Supplementary Information

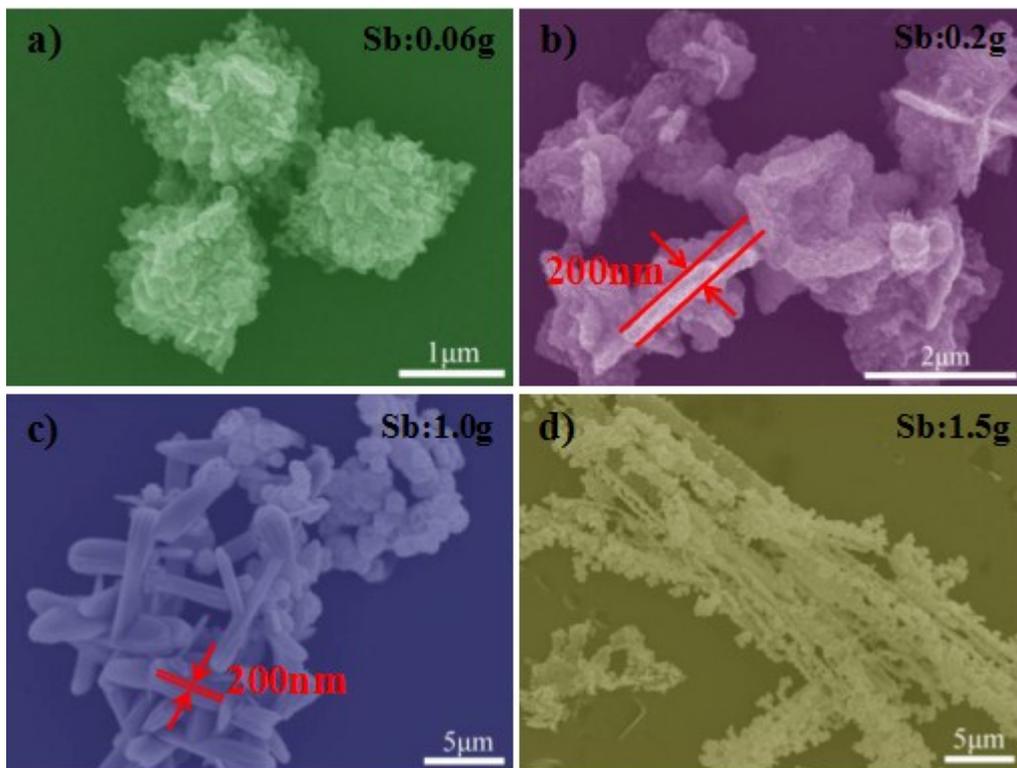
### **Enhanced thermoelectric performance of $\text{Cu}_3\text{SbS}_4$ flower-like hierarchical architectures composed of Cl doped nanoflakes via an in situ generated CuS template**

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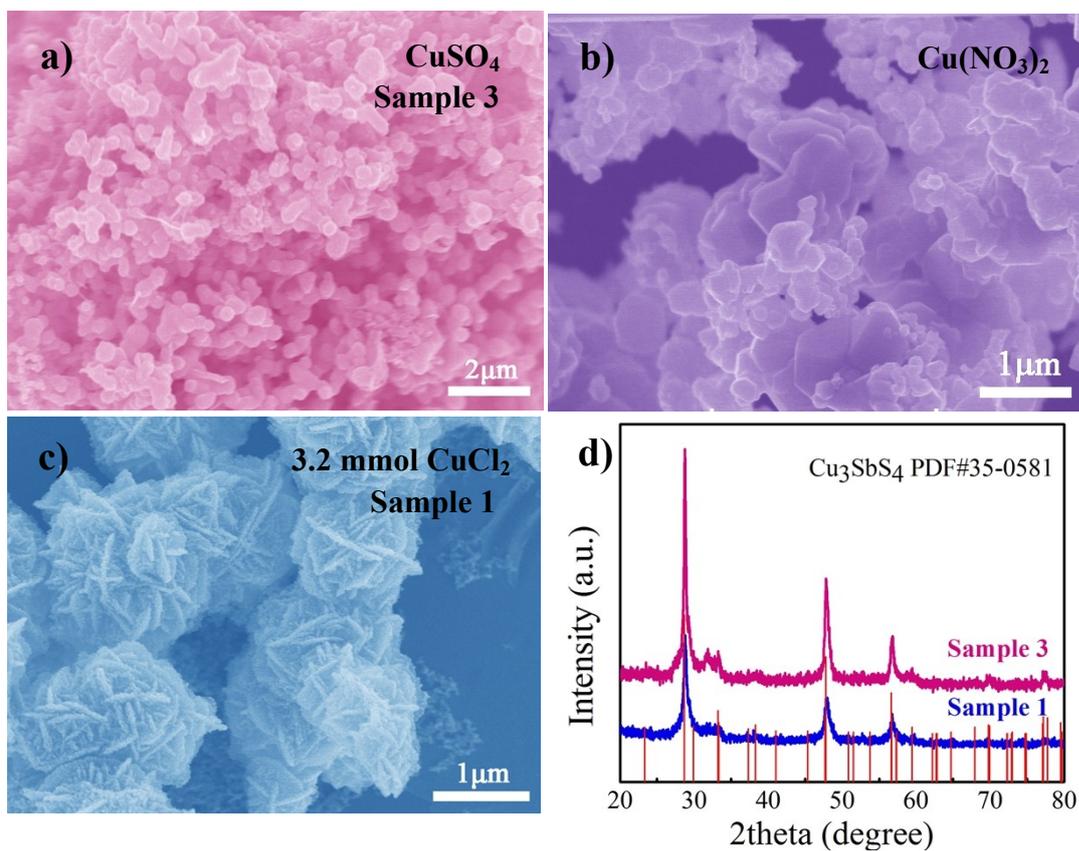
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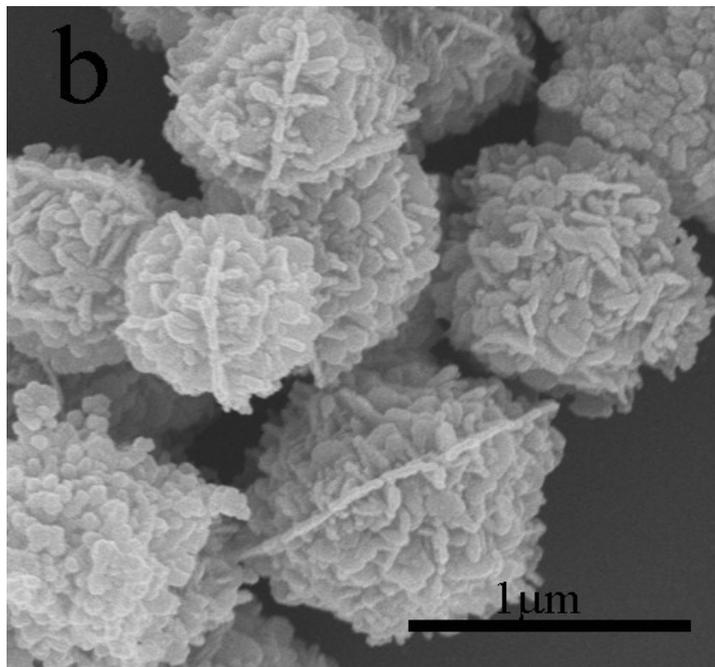
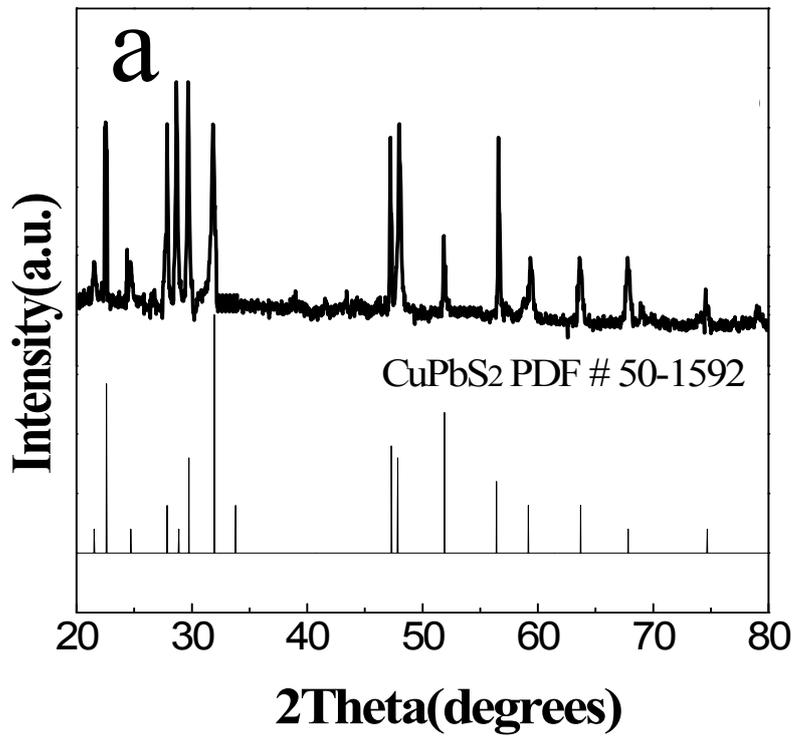
**Fig.S1.** SEM images of as-prepared samples synthesized with different amounts of Sb source (a-d) 0.06 g (0.09 mmol); 0.2 g (0.30 mmol); 1.0 g (1.48 mmol); 1.5 g (2.22 mmol), respectively.



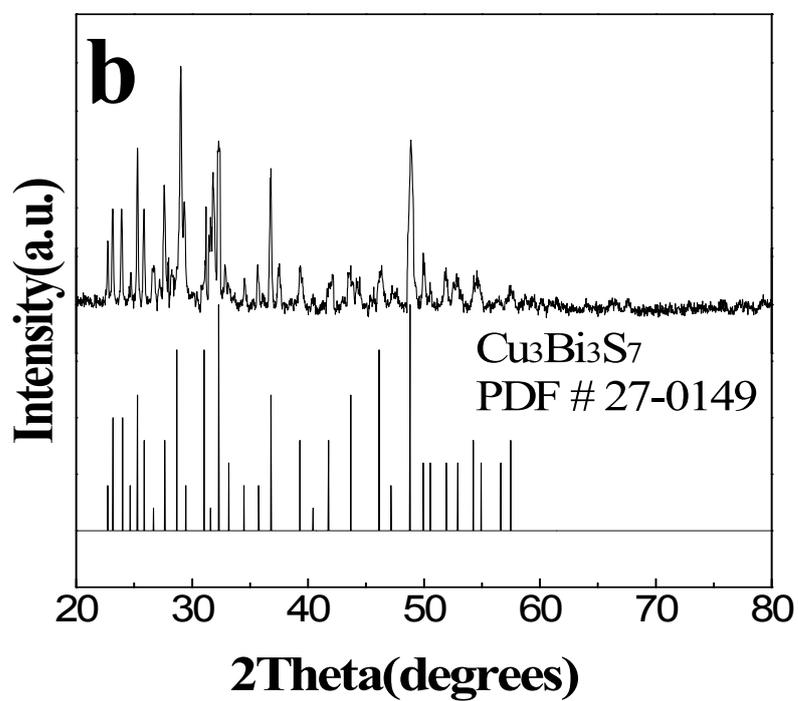
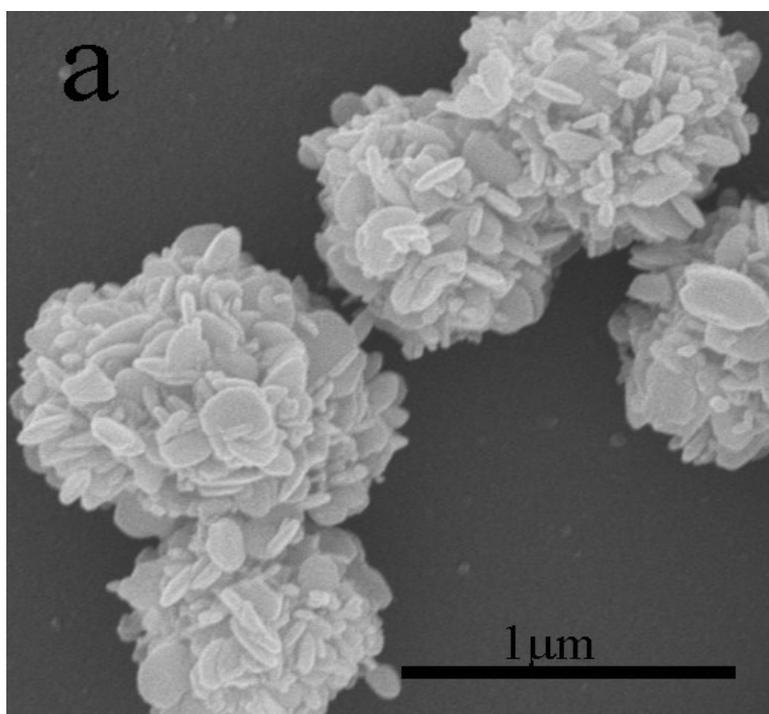
**Fig.S2.** SEM images of samples obtained by solvothermal treatment after introducing (a)  $\text{CuSO}_4$  (Sample 3), (b)  $\text{Cu}(\text{NO}_3)_2$  and (c) 3.2 mmol  $\text{CuCl}_2$  as Cu precursor (Sample 1), respectively. (d) The corresponding XRD patterns of Sample 1 and 3.

Table S1. Lattice parameters (a and c), chemical composition, band gap of the Cl-free and Cl-doped  $\text{Cu}_3\text{SbS}_4$  at 300 K. The values in parentheses are the statistical errors. Other errors such as temperature fluctuations (<1 K) should be considered for a and c.

Sample	Lattice parameters(Å)		Cl adding amount	chemical composition	band gap (eV)
	a	c			
Sample 1	5.3842(1)	1.0764(2)	3.2mmol	$\text{Cu}_{3.8}\text{SbS}_{3.8}\text{Cl}_{0.9}$	1.06
Sample 2	5.3841(3)	1.0763(1)	1.6mmol	$\text{Cu}_{3.2}\text{SbS}_{3.8}\text{Cl}_{0.3}$	1.09
Sample 3	5.3840(2)	1.0762(2)	0 mmol	$\text{Cu}_{2.8}\text{SbS}_{3.8}$	0.98



**Fig. S3** Powder X-ray diffraction pattern (a) and SEM image (b) of CuPbS<sub>2</sub> microspheres.



**Fig. S4** SEM image (a) and powder X-ray diffraction pattern (b) of  $\text{Cu}_3\text{Bi}_3\text{S}_7$  microspheres.

Table S2. A summary of *n* or *p* type semiconductor conduction behavior, room temperature Hall carrier concentration ( $n_H$ ), and mobility ( $\mu_H$ ) of the Cl-doped  $\text{Cu}_3\text{SbS}_4$  pellets.

Pellet	Cl adding amount	behavior	$n_H$ [ $\text{cm}^{-3}$ ]	$\mu_H$ [ $\text{cm}^2\text{V}^{-1}\text{s}^{-1}$ ]
Sample 2	1.6mmol	p-type	$3.9 \times 10^{19}$	1.87
Sample 4	6.4mmol	n-type	$2.2 \times 10^{20}$	0.32